

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A Final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

Technical Contact:  
 Name: Yang, Johnson  
 E-mail: Johnson.Yang@fairchildsemi.com  
 Phone:

PCN Originator:  
 Name: Sun, Brian  
 E-mail: Brian.Sun@fairchildsemi.com  
 Phone:

Implementation of change:  
 Expected 1st Device Shipment Date: 2007/12/31

Earliest Year/Work Week of Changed Product: 0748

Change Type Description: Alternate Assembly/Test Location/Qualification

Description of Change (From): SPS

Description of Change (To): Fairchild Suzhou China

Reason for Change : To meet increased customer demand and 2nd source

Qual/REL Plan Numbers : Q20070223

**Qualification :**

Fairchild Semiconductor (Suzhou) Co., LTD (FSSZ) is being qualified as an alternative assembly and test site as part of Fairchild Semiconductor's ongoing effort to increase manufacturing capacity for our various products assembled in the TO264 3 leads packages.

**Qualification Stress Test and Sample Size Detail**

Device #1	FJL4315OTU
Package:	-1
#Leads:	-1

**Environment Stress Detail:**

Stress	P/C	Standard	Conditions	Readpoints			Samples
				TP1	TP2	TP3	
ACLV		JESD22-A102	100%RH, 121 degree C	96			77

H3TRB		JESD22-A101B	85%RH, 85 degree C, 80% of Rated BV	168	500	1000	77
HTRB		JESD22-A108	150 degree C, 80% of Rated BV	168	500	1000	77
HTSL		JESD22-A103	150 degree C	168	500	1000	77
PRCL		MIL-STD-750-1036	Delta 100 degree C, 5 Min on/off	3000	6000		77
TMCL3		JESD22-A104	-55 degree C, 150 degree C	500	1000		77

Device #2	FQL40N50
Package:	
#Leads:	

Environment Stress Detail:

Stress	P/C	Standard	Conditions	Readpoints			Samples
				TP1	TP2	TP3	
ACLV		JESD22-A102	100%RH, 121 degree C	96			77
H3TRB		JESD22-A101B	85%RH, 85 degree C, 80% of Rated BV	168	500	1000	77
HTGB		JESD22-A108	150 degree C, 100 % Rated VgsV	168	500	1000	77
HTRB		JESD22-A108	150 degree C, 80% of Rated BV	168	500	1000	77
HTSL		JESD22-A103	150 degree C	168	500	1000	77
PRCL		MIL-STD-750-1036	Delta 100 degree C, 5 Min on/off	3000	6000		77
TMCL3		JESD22-A104	-55 degree C, 150 degree C	500	1000		77

Device #3	SGL40N150DTU
Package:	-1
#Leads:	-1

Environment Stress Detail:

Stress	P/C	Standard	Conditions	Readpoints			Samples
				TP1	TP2	TP3	
ACLV		JESD22-A102	100%RH, 121 degree C	96			77
H3TRB		JESD22-A101B	85%RH, 85 degree C, 80% of Rated BV	168	500	1000	77
HTGB		JESD22-A108	150C, 100 % Rated VgsV	168	500	1000	77
HTRB		JESD22-A108	150C, 80% of Rated BV	168	500	1000	77
HTSL		JESD22-A103	150 degree C	168	500	1000	77
PRCL		MIL-STD-750-1036	Delta 100 degree C, 5 Min on/off	3000	6000		77
TMCL3		JESD22-A104	-55 degree C, 150 degree C	500	1000		77

Product Id Description :

Affected FSIDs :

FGL40N120ANDTU	FGL40N120ANDTU_NL	FGL40N120ANTU
FGL60N100BNTD	FGL60N100BNTDTU	FGL60N100BNTDTU_NL
FGL60N100BNTD_NL	FJL4215OTU	FJL4215OTU_NL

FJL4315OTU	FJL4315OTU_NL	FQL40N50
FQL40N50F	FQL50N40	SGL160N60UFDTU
SGL160N60UFDTU_NL	SGL160N60UFTU	SGL40N150DTU
SGL40N150DTU_NL	SGL40N150TU	SGL50N60RUFDTU
SGL60N90DG3TU	SGL60N90DG3TU_NL	